

Nico Kaiser

List of Publications by Year in descending order

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Version: 2024-02-01

11
papers

191
citations

1307594

7
h-index

1372567

10
g-index

11
all docs

11
docs citations

11
times ranked

219
citing authors

#	ARTICLE	IF	CITATIONS
1	Forming-Free Grain Boundary Engineered Hafnium Oxide Resistive Random Access Memory Devices. <i>Advanced Electronic Materials</i> , 2019, 5, 1900484.	5.1	57
2	Defect-Stabilized Substoichiometric Polymorphs of Hafnium Oxide with Semiconducting Properties. <i>ACS Applied Materials & Interfaces</i> , 2022, 14, 1290-1303.	8.0	27
3	Analysis and simulation of the multiple resistive switching modes occurring in HfO _x -based resistive random access memories using memdiodes. <i>Journal of Applied Physics</i> , 2019, 125, .	2.5	26
4	Enhanced thermal stability of yttrium oxide-based RRAM devices with inhomogeneous Schottky-barrier. <i>Applied Physics Letters</i> , 2020, 117, .	3.3	26
5	Tailoring the Switching Dynamics in Yttrium Oxide-Based RRAM Devices by Oxygen Engineering: From Digital to Multi-Level Quantization toward Analog Switching. <i>Advanced Electronic Materials</i> , 2020, 6, 2000439.	5.1	20
6	Role of Oxygen Defects in Conductive-Filament Formation in Y ₂ O ₃ -Based Analog RRAM Devices as Revealed by Fluctuation Spectroscopy. <i>Physical Review Applied</i> , 2020, 14, .	3.8	15
7	Defect-Induced Phase Transition in Hafnium Oxide Thin Films: Comparing Heavy Ion Irradiation and Oxygen-Engineering Effects. <i>IEEE Transactions on Nuclear Science</i> , 2021, 68, 1542-1547.	2.0	12
8	Machine Learning Assisted Pattern Matching: Insight into Oxide Electronic Device Performance by Phase Determination in 4D-STEM Datasets. <i>Microscopy and Microanalysis</i> , 2020, 26, 1908-1909.	0.4	3
9	Heavy Ion Irradiation Effects on Structural and Ferroelectric Properties of HfO ₂ Films. , 2020, , .		3
10	Correlation of Structural Modifications by Multiscale Phase Mapping in Filamentary Type HfO ₂ -based RRAM: Towards a Component Specific in situ TEM Investigation. <i>Microscopy and Microanalysis</i> , 2019, 25, 1842-1843.	0.4	1
11	Enhanced Conductivity and Microstructure in Highly Textured TiN _{1-x} /Al ₂ O ₃ Thin Films. <i>ACS Omega</i> , 2022, 7, 2041-2048.	3.5	1